

SLOVENSKI STANDARD
oSIST prEN IEC 61000-4-29:2026
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Elektromagnetna združljivost (EMC) - 4-29. del: Preskusne in merilne tehnike - Preskusi odpornosti proti upadom napetosti, kratkotrajnim prekinitvam in odklonom napetosti za enosmerni (DC) napajalni priključek

Electromagnetic compatibility (EMC) - Part 4-29: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations on d.c. input power port immunity tests

Elektromagnetische Verträglichkeit (EMV) - Teil 4-29: Prüf- und Messverfahren - Prüfungen der Störfestigkeit gegen Spannungseinbrüche, Kurzzeitunterbrechungen und Spannungsschwankungen an Gleichstrom-Netzeingängen

Compatibilité électromagnétique (CEM) - Partie 4-29: Techniques d'essai et de mesure - Essais d'immunité aux creux de tension, coupures brèves et variations de tension sur les accès d'alimentation en courant continu

Ta slovenski standard je istoveten z: prEN IEC 61000-4-29:2026

ICS:

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77A/1276/CDV

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SECRETARIAT: France	SECRETARY: Mr Cédric LAVENU
OF INTEREST TO THE FOLLOWING COMMITTEES:	HORIZONTAL FUNCTION(S):
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TITLE:

Electromagnetic compatibility (EMC) - Part 4-29: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations on d.c. input power port immunity tests

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTROMAGNETIC COMPATIBILITY (EMC) –**Part 4-29: Testing and measurement techniques –
Voltage dips, short interruptions and voltage variations
on DC input power port immunity tests****FOREWORD**

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IEC 61000-4-29 has been prepared by subcommittee 77A: EMC – Low frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility. It is an International Standard.

It forms part 4-29 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107.

This second edition cancels and replaces the first edition published in 2000. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) Increase the output voltage of the test generator to take into account new DC networks voltages;

- 114 b) Provision of tolerances for the duration of the voltage changes
 115 c) Limitation of the current when applying short interruptions in low impedance condition
 116 d) General technical clarifications for the specifications of the test generator and their
 117 verification
 118 e) Clarifications regarding the loads used to verify the switching characteristics and the peak
 119 inrush current drive capability of the test generator
 120 f) Clarifications regarding the evaluation of test results and test reports
 121 g) Description of the DC environment

122 The text of this International Standard is based on the following documents:

Draft	Report on voting
XX/XX/FDIS	XX/XX/RVD

123
 124 Full information on the voting for its approval can be found in the report on voting indicated in
 125 the above table.

126 The language used for the development of this International Standard is English.

127 This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in
 128 accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available
 129 at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are
 130 described in greater detail at www.iec.ch/publications.

131 A list of all parts in the IEC 61000 series, published under the general title *Electromagnetic*
 132 *compatibility (EMC)*, can be found on the IEC website.

133 The committee has decided that the contents of this document will remain unchanged until the
 134 stability date indicated on the IEC website under webstore.iec.ch in the data related to the
 135 specific document. At this date, the document will be

- 136 • reconfirmed,
- 137 • withdrawn, or
- 138 • revised.

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